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**List of ScanWave™ or sMIM publications etc.**:

1. Johnston, S. R., Ma, E. Y., & Shen, Z. X. (2018). Optically coupled methods for microwave impedance microscopy. *Review of Scientific Instruments*. https://doi.org/10.1063/1.5011391
2. Johnston, S. R., Yang, Y., Cui, Y. T., Ma, E. Y., Kämpfe, T., Eng, L. M., … Shen, Z. X. (2017). Measurement of surface acoustic wave resonances in ferroelectric domains by microwave microscopy. *Journal of Applied Physics*. https://doi.org/10.1063/1.4997474
3. Cui, Y. T., Ma, E. Y., & Shen, Z. X. (2016). Quartz tuning fork based microwave impedance microscopy. *Review of Scientific Instruments*. https://doi.org/10.1063/1.4954156
4. Wei, Z., Cui, Y. T., Ma, E. Y., Johnston, S., Yang, Y., Chen, R., … Chen, X. (2016). Quantitative theory for probe-sample interaction with inhomogeneous perturbation in near-field scanning microwave microscopy. *IEEE Transactions on Microwave Theory and Techniques*. https://doi.org/10.1109/TMTT.2016.2537801
5. Lai, K., Nakamura, M., Kundhikanjana, W., Kawasaki, M., Tokura, Y., Kelly, M. A., & Shen, Z.-X. (2010). Microwave imaging of mesoscopic percolating network in a manganite thin film. *ArXiv.Org, e-Print Archive, Condensed Matter*.
6. Ma, E. Y., Bryant, B., Tokunaga, Y., Aeppli, G., Tokura, Y., & Shen, Z. X. (2015). Charge-order domain walls with enhanced conductivity in a layered manganite. *Nature Communications*, *6*(May), 1–6. https://doi.org/10.1038/ncomms8595
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10. Manganites, R., Wu, X., Petralanda, U., Zheng, L., Ren, Y., Hu, R., & Cheong, S. (2017). Low-energy Structural Dynamics of Ferroelectric Domain Walls in Hexagonal I . *ArXiv:1702.06205*, (May), 1–9.
11. Johnston, S. R., Ma, E. Y., & Shen, Z. X. (2018). Optically coupled methods for microwave impedance microscopy. *Review of Scientific Instruments*. https://doi.org/10.1063/1.5011391
12. Lai, K., Peng, H., Kundhikanjana, W., Schoen, D. T., Xie, C., Meister, S., … Shen, Z. X. (2009). Nanoscale electronic inhomogeneity in In2Se3nanoribbons revealed by microwave impedance microscopy. *Nano Letters*, *9*(3), 1265–1269. https://doi.org/10.1021/nl900222j

13. Lai, K., Kundhikanjana, W., Peng, H., Cui, Y., Kelly, M. A., & Shen, Z. X. (2009). Tapping mode microwave impedance microscopy. *Review of Scientific Instruments*, *80*(4). https://doi.org/10.1063/1.3123406
14. Scrymgeour, D. A., Baca, A., Fishgrab, K., Simonson, R. J., Marshall, M., Bussmann, E., … Misra, S. (2017). Determining the resolution of scanning microwave impedance microscopy using atomic-precision buried donor structures. *Applied Surface Science*, *423*, 1097–1102. https://doi.org/10.1016/j.apsusc.2017.06.261
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